

MCR8DSM, MCR8DSN



Description

Designed for high volume, low cost, industrial and consumer applications such as motor control; process control; temperature, light and speed control.

Features

- Small Size
- Passivated Die for Reliability and Uniformity
- Low Level Triggering and Holding Characteristics
- Available in Two Package Styles Surface Mount Lead Form – Case 369C Miniature Plastic Package – Straight Leads – Case 369
- Epoxy Meets UL 94 V-0 @ 0.125 in

Po

- ESD Ratings: Human Body Model, 3B > 8000 V Machine Model, C > 400V
- Pb–Free Packages are Available

Pin Out



Functional Diagram



Additional Information







Samples



Maximum Ratings	(T _J = 25°C unless	otherwise noted)
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Rating		Symbol	Value	Unit
Peak Repetitive Off–State Voltage (Note 1) $(T_j=-40 \text{ to } 110^{\circ}\text{C}$, Sine Wave, 50 to 60 Hz)	MCR8DSM MCR8DSN	V _{drm} , V _{rrm}	600 800	V
On-State RMS Current (180° Conduction Angles; $T_c = 90$ °C)		I _{T (RMS)}	8.0	А
Average On–State Current (180° Conduction Angles; $T_c = 90$ °C)		I _{T(AV)}	5.1	А
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, T _J = 110°C)		I _{TSM}	90	А
Circuit Fusing Consideration (t = 8.3 ms)		l²t	34	A ² sec
Forward Peak Gate Power (Pulse Width \leq 10 $\mu sec, T_c$ = 90°C)		P _{GM}	5.0	W
Forward Average Gate Power (t = 8.3 msec, $T_c = 90^{\circ}$ C)		P _{GM (AV)}	0.5	W
Forward Peak Gate Current (Pulse Width \leq 10 $\mu sec,T_c =$ 90°C)		I _{GM}	2.0	А
Operating Junction Temperature Range		TJ	-40 to 110	°C
Storage Temperature Range		T _{stg}	-40 to 150	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

Thermal Characteristics						
Rating	Symbol	Value	Unit			
Thermal Resistance, Junction-to-Case	R _{eJC}	2.2				
Thermal Resistance, Junction-to-Ambient	R _{eja}	88	°C/W			
Thermal Resistance, Junction-to-Ambient (Note 2)	R _{eja}	80				
Maximum Lead Temperature for Soldering Purposes 1/8" from Case for 10 Seconds	TL	260	°C			

Electrical Characteristics - OFF (T₁ = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Repetitive Forward or Reverse Blocking Current (Note 3)	$T_J = 25^{\circ}C$	I _{DBM} ,	-	-	10	
(V_{AK} = Rated V_{DRM} \text{ or } V_{RRM'} R_{GK} = 1.0 \text{ k}\Omega	$T_{_{\rm J}} = 110^{\circ}{\rm C}$	I _{RRM}	-	-	500	μΑ

Electrical Characteristics - **ON** ($T_1 = 25^{\circ}C$ unless otherwise noted; Electricals apply in both directions)

Characteristic		Symbol	Min	Тур	Max	Unit
Peak Reverse Gate Blocking Voltage (I_{gR} = 10 μ A)		V _{grm}	10	12.5	18	V
Peak Reverse Gate Blocking Current (V_{gR} = 10 V)		I _{RGM}	_	_	1.2	μA
Peak Forward On–State Voltage (Note 4) ($I_{TM} = 16 \text{ A}$)		V _{TM}	-	1.4	1.8	V
Gate Trigger Current (Continuous dc) (Note 5) (V _{AK} = 12 Vdc, R _L = 100 Ω)	$(T_{J} = 25^{\circ}C)$ $(T_{J} = -40^{\circ}C)$	I _{GT}	5.0 -	12 -	200 300	μA
Gate Trigger Voltage (Continuous dc) ($V_{\rm D}$ = 12 V, R _L = 100 Ω) (Note 5)	(T _J = 25°C) (T _J = -40°C) (T _J = 110°C)	V _{gt}	0.45 	0.65 - -	1.0 1.5 -	V
Holding Current (V _D = 12 V, Initiating Current = 200 mA, R _{GK} = 1 kΩ)	(T _J = 25°C) (T _J = -40°C)	I _H	0.5	1.0	6.0 10	mA
Latching Current (V_{_{D}} = 12 V, IG = 2.0 mA, R_{_{GK}} = 1 k\Omega)	$(T_{J} = 25^{\circ}C)$ $(T_{J} = -40^{\circ}C)$	I _L	0.5 -	1.0 -	6.0 10	mA
Total Turn–On Time (Source Voltage = 12 V, $R_s = 6.0 \text{ k}\Omega$, IT = 16 A(pk), $R_{_{GK}} = 1.0 \text{ k}\Omega$ Rise Time = 20 ns, Pulse Width = 10 µs)) (VD = Rated V_{DRM} ,	tgt	_	2.0	5.0	μs



Dynamic Characteristics					
Characteristic	Symbol	Min	Тур	Max	Unit
Critical Rate of Rise of Off–State Voltage ($V_D = 0.67 \text{ X Rated } V_{DRM'}$ Exponential Waveform, $R_{GK} = 1.0 \text{ k}\Omega$, $T_J = 110^{\circ}\text{C}$)	dv/dt	2.0	10	_	V/µs

2. Surface mounted on minimum recommended pad size.

3. Ratings apply for negative gate voltage or RGK = 1.0 kQ. Devices shall not have a positive gate voltage concurrently with a negative voltage on the anode. Devices should not be tested with a constant current source for forward and reverse blocking capability such that the voltage applied exceeds the rated blocking voltage.

4. Pulse Test; Pulse Width \leq 2.0 msec, Duty Cycle \leq 2%.

5. RGK current not included in measurements.

Voltage Current Characteristic of SCR

Symbol	Parameter
V _{drm}	Peak Repetitive Forward Off State Voltage
I _{DRM}	Peak Forward Blocking Current
V _{RRM}	Peak Repetitive Reverse Off State Voltage
I _{RRM}	Peak Reverse Blocking Current
V _{TM}	Maximum On State Voltage
I _H	Holding Current





Figure 2. On-State Power Dissipation





Figure 3. On–State Characteristics



Figure 4. Transient Thermal Response



Figure 5. Typical Gate Trigger Current vs Junction Temperature 1000 GT, GATE TRIGGER CURRENT (µA) $R_{GK} = 1.0 \text{ K}\Omega$ 100 GATE OPEN 10 1.0 **2**5 40 **1**0 50 20 35 50 65 80 95 110

Figure 6. Typical Gate Trigger Voltage vs Junction Temperature



Figure 8. Typical Latching Current vs Junction Temperature



Figure 7. Typical Holding Current vs Junction Temperature

TJ, JUNCTION TEMPERATURE (C)





Figure 9. Holding Current versus Gate–Cathode Resistance

Figure 10. Exponential Static dv/dt vs Gate–Cathode Resistance and Junction Temperature

Figure 11. Exponential Static dv/dt vs Gate–Cathode Resistance and Peak Voltage



Figure 12. Exponential Static dv/dt vs Gate–Cathode Resistance and Gate Trigger Current Sensitivity





Dimensions



Dim	Inc	hes	Millin	neters	
Dim	Min	Мах	Min	Мах	
Α	0.087	0.094	2.20	2.40	
A1	0.000	0.005	0.00	0.12	
b	0.022	0.030	0.55	0.75	
b2	0.026	0.033	0.65	0.85	
b3	0.209	0.217	5.30	5.50	
C	0.019	0.023	0.49	0.59	
c2	0.019	0.023	0.49	0.59	
D	0.213	0.224	5.40	5.70	
E	0.252	0.260	6.40	6.60	
е	0.0	91	2.30		
Н	0.374	0.406	9.50	10.30	
L	0.058	0.070	1.47	1.78	
L1	0.114		2.90		
L2	0.020		0.	51	
L3	0.053	0.065	1.35	1.65	
L4	0.028	0.039	0.70	1.00	
Z	0.154	-	3.90	-	

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.



4. MT2

Soldering Footprint



Part Marking System



Pin Assignment			
1	Cathode		
2	Anode		
3	Gate		
4	Anode		

Ordering Information					
Device	Package	Shipping			
MCR8DSMT4	DPAK				
MCR8DSMT4G	DPAK (Pb–Free)	2500/Tane & Beel			
MCR8DSNT4	DPAK	2300/1806 & Neel			
MCR8DSNT4G	DPAK (Pb-Free)				

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